

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination YASUNAGA ET AL.	
		Examiner Cynthia Calderon	Art Unit 2622	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,385,772	05-2002	Courtney, Jonathan D.	725/105
*	B US-2002/0104092	08-2002	Arai et al.	725/87
*	C US-7,186,271	03-2007	Horikiri et al.	726/35
*	D US-6,931,661	08-2005	Smith, Edwin Derek	725/133
*	E US-2001/0008415	07-2001	Park, Chun-Ho	348/143
*	F US-2006/0028555	02-2006	Fredlund, John R.	348/211.4
*	G US-7,286,145	10-2007	Sunata, Jin	345/671
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	EP0967584A2	12-1999	EP	Texas Instruments Inc	G08B 13/194
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.